SW Test Workshop

• **SW Test is a Probe Technology Forum ...**
  – Focused Technical Workshop for Wafer Test Professionals
  – Practical solutions to real problems
  – Balanced mix of semiconductor manufacturer, supplier, and collaborative presentations

• **Informal Conference ...**
  – Friendly and relaxed format focused on technical exchange
  – Great social activities to facilitate networking and informal discussions
  – Meet new people, talk about probe and technology, and have some fun!

• **Twenty-Six Years of Probe Technology ...**
  – Starting with 40 participants in 1990, more than 8000 attendees have come from around the world to discuss probe technology at SW Test.

SW Test Workshop - June 4-7, 2017
SW Test Workshop Program

- **Technical Program**
  - Technical Tutorial from subject experts
  - Keynote from key technologist in the wafer test industry
  - Nine Focused Technical Sessions across three days
  - Overall 32 Podium Presentations

- **EXPO Program ... (Sold out for past 5-years)**
  - Two EXPO sessions that do not compete with Technical Program
  - 42 booths for probe card, probe equipment, and related service suppliers

- **Corporate Support Program**
  - Platinum Sponsors ... (10 sponsors in 2016)
  - Gold Sponsors ... (3 sponsors in 2016)
  - Silver Sponsors ... (4 sponsors in 2016)
SW Test Organization

- **Executive Team**
  - Jerry Broz, Ph.D., General Chair and Sr. Member IEEE
  - Rey Rincon, Technical Program Chair
  - Maddie Harwood, Finance Chair

- **Program Committee ...**
  - John Caldwell (Micron Technology)
  - Darren James (Rudolph Technologies)
  - Gary Maier (IBM)
  - Patrick Mui (JEM America)

- **Steering Committee ...**
  - Gunther Boehm (FeinMetall GmbH)
  - Michael Huebner, Ph.D. (FormFactor)
  - Amy Leong (Formfactor)
  - Clark Liu (PTI - Taiwan)
  - Mark Ojeda (Spansion)
  - Fred Taber (Taber Consulting)
  - Joey Wu (MPI - Taiwan)
  - Karen Armendariz (Celadon Systems)
  - Stevan Hunter, Ph.D. (ON Semi)
  - Al Wegleitner (Texas Instruments)
  - Sang Kyu (SK) Yoo (Samsung – Korea)

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Industry Partnerships

- IEEE Holm Conference on Electrical Contacts
  http://www.ieee-holm.org

- SEMICON West Test Forum 2016
  http://www.semiconwest.org/test-forum

- Burn In & Test Strategies Workshop
  http://www.bitsworkshop.org

- IS-Test Workshop
  http://www.is-test.com

- Electronic Components and Technology Conference
  http://www.ectc.net

- ProbeCard Insider
  Technology Blog by Paul Meyer focused on Probe Cards
  http://probecardinsider.com
19 out of the 32 Podium Presentations had at least one international author!

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SW Test 2016 Attendee Demographics

SW Test 2016
465 Attendees

- IDM / Foundry / Test: 21%
- Wafer Probing Tools: 6%
- Probe Metrology Tools: 2%
- ATE Equipment: 9%
- Probe Materials Supplier: 6%
- Probe Infrastructure Tooling: 6%
- PCB Design / Manufacturing: 5%
- Probe Card Supplier: 39%
- Other: 6%

J. Broz
SW Test Workshop - June 4-7, 2017
Recognition & Awards

- Most “Inspirational” Presentation
- Best Presentation, Tutorial in Nature
- Best Data Presented
- Best Overall Presentation

- Award winning Presentations from SW Test 2016 presented at SEMICON West Test Forum, July 12, 2016
SW Test 2016 Awards

Best Presentation, Tutorial in Nature

Production Test RF Calibration for Multi-DUT Probe Cards: How to get the most accurate measurements

Daniel Bock, Ph.D. (Cascade Microtech, USA)

Best Overall Presentation

Probing Cu Pillar Application w/ Vertical Technologies

Brandon Mair (Texas Instruments, Inc., USA)
27th SW Test, June 4 to 7, 2017

Abstract Submission for 2017 will be available soon!

Rancho Bernardo Inn
San Diego, CA

SW Test Workshop - June 4-7, 2017
Thanks for Attending Semicon West

See you again in San Diego !!!

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